

NenoVision

NenoVision is a technology company developing and manufacturing a unique **atomic force microscope (AFM) LiteScope™**, designed for fast and easy integration into scanning electron microscopes (SEMs). It allows scientists do measurements and analyses, which are normally nearly to impossible, time consuming or very expensive.

MAIN BENEFITS OF AFM-in-SEM SOLUTION

- **Complex and correlative sample analysis**

A unique method of multidimensional correlative imaging (CPEM) enables **simultaneous acquisition** of the data from SEM and AFM, and their seamless **correlation into 3D images**.

- **In-situ sample characterization**

Both AFM and SEM measurements are done at the **same time**, in the **same place** and under the **same conditions**, preventing sample contamination, transfer or degradation of sensitive samples.

- **Precise localization of the region of interest**

An extremely precise and **time-saving** approach uses SEM to localize and navigate the AFM tip to the region of interest.

AFM-in-SEM CORRELATIVE MICROSCOPY, FUTURE OF NANO-SCALE IMAGING

NenoVision has developed a unique technique for correlative measurements called CPEM™ (Correlative Probe and Electron Microscopy). CPEM enables to **simultaneously acquire various AFM and SEM signals** covering surface topography, mechanical, electrical, electromechanical and magnetic properties, SE, BSE, and other SEM images. **The CPEM technology allows various AFM and SEM signals to be directly correlated** with exceptional precision into 3D images.

PRINCIPAL MEASUREMENT MODES

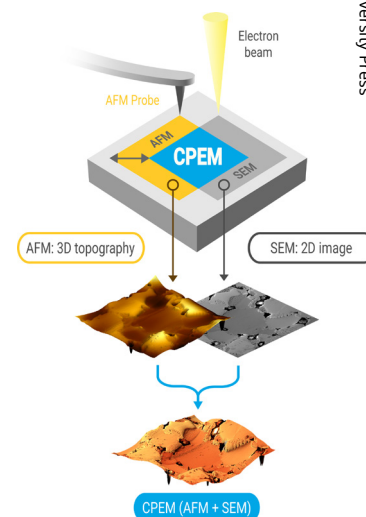
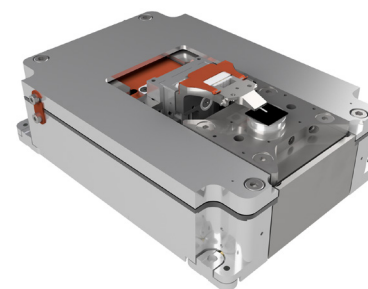
- Topography (AFM)
- Mechanical (Energy Dissipation, FMM, Nanoindentation)
- Electrical (C-AFM, KPFM)
- Magnetic (MFM)
- Electro-mechanical (PFM)
- Spectroscopy modes (F-z curves, I-V curves)

MAIN APPLICATION AREAS

- **Material science** (1D and 2D materials, Steels & metal alloys, Batteries, Ceramics, Polymers & Composites)
- **Nanostructures** (Modified surfaces FIB/GIS, Quantum dots, Nanostructured films, Nano-patterning, Nanowires, EBIC, ToF-SIM etc.)
- **Semiconductors** (Integrated circuits, Solar cells, MEMS/NEMS, Failure analyses, Dopant visualization, Current leakage localization)
- **Life science** (Cell biology, Marine biology, Protein technology)



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How to find us

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